

VCRRP-Channel Enhancement Mode Power MOSFET

Description

The VCRR60P09K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is well suited for use as a load switch or in PWM applications.

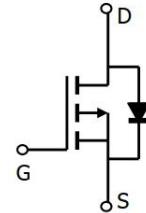
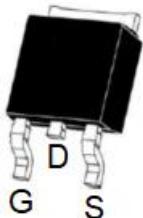
Application

- Load switch
- PWM application

General Features

- $V_{DS} = -60V, I_D = -9A$
- $R_{DS(ON)} < 173m\Omega @ V_{GS} = -10V \quad I_D = -7A$
- $R_{DS(ON)} < 210m\Omega @ V_{GS} = -10V \quad I_D = -9A$
- $R_{DS(ON)} < 220m\Omega @ V_{GS} = -4.5V \quad I_D = -4A$
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation
- 175 °C operating temperature
- Pb-free lead plating

TO-252



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VCRR60P09K	VCRR60P09K	TO-252	Ø330mm	16mm	2500 units

Absolute Maximum Ratings ($T_c = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	-9	A
Pulsed Drain Current (Note 1)	I_{DM}	-36	A
Maximum Power Dissipation	P_D	40	W
Single pulse avalanche energy (Note 5)	E_{AS}	24	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	°C

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 2)	$R_{\theta JC}$	3.75	°C/W
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Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

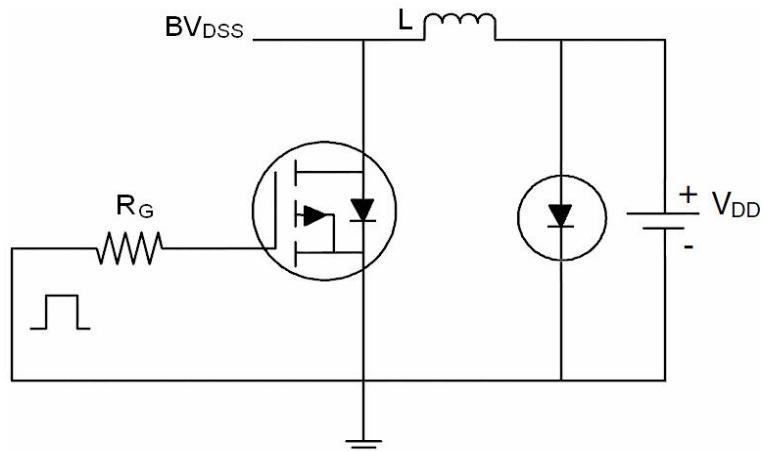
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-60	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=-60\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1.4	-2.0	-2.6	V
Drain-Source On-State Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-7\text{A}$	-	-	173	$\text{m}\Omega$
		$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-9\text{A}$	-	-	210	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-4\text{A}$	-	-	220	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$V_{\text{DS}}=-5\text{V}, I_{\text{D}}=-9\text{A}$	-	3	-	S
Dynamic Characteristics (Note 4)						
Input Capacitance	C_{iss}	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	444.2	-	PF
Output Capacitance	C_{oss}		-	19.6	-	PF
Reverse Transfer Capacitance	C_{rss}		-	17.9	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=-30\text{V}, I_{\text{D}}=-9\text{A}, V_{\text{GS}}=-10\text{V}, R_{\text{G}}=3\Omega$	-	40	-	nS
Turn-on Rise Time	t_{r}		-	35	-	nS
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$		-	15	-	nS
Turn-Off Fall Time	t_{f}		-	10	-	nS
Total Gate Charge	Q_{g}	$V_{\text{DS}}=-30, I_{\text{D}}=-9\text{A}, V_{\text{GS}}=-10\text{V}$	-	11.3	-	nC
Gate-Source Charge	Q_{gs}		-	2.7	-	nC
Gate-Drain Charge	Q_{gd}		-	1.6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{s}}=-9\text{A}$	-		-1.2	V
Diode Forward Current (Note 2)	I_{s}		-	-	-9	A
Reverse Recovery Time	t_{rr}	$T_{\text{J}} = 25^\circ\text{C}, I_{\text{F}} = -9\text{A}$ $dI/dt = -100\text{A}/\mu\text{s}$ (Note 3)	-	25		nS
Reverse Recovery Charge	Q_{rr}		-	31		nC

Notes:

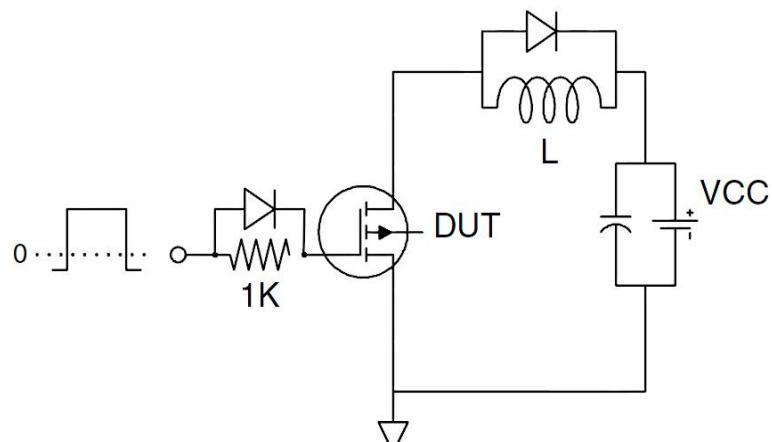
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition : $T_j=25^\circ\text{C}, V_{\text{DD}}=-30\text{V}, V_{\text{G}}=-10\text{V}, L=0.5\text{mH}, R_g=25\Omega$

Test Circuit

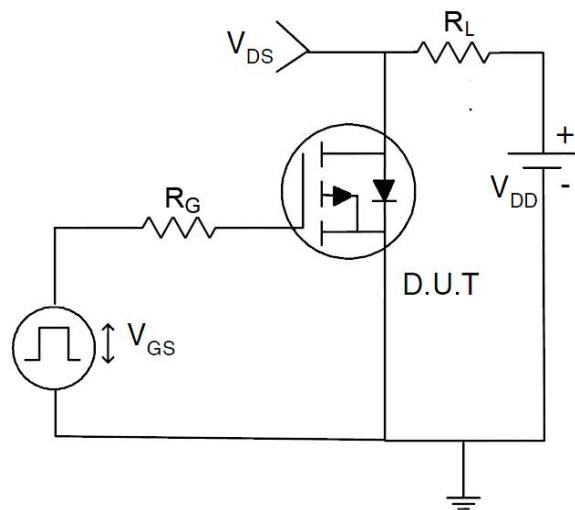
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

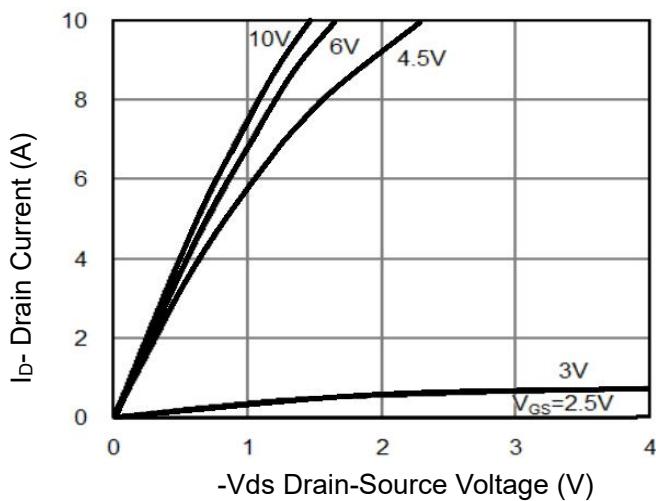


Figure 1 Output Characteristics

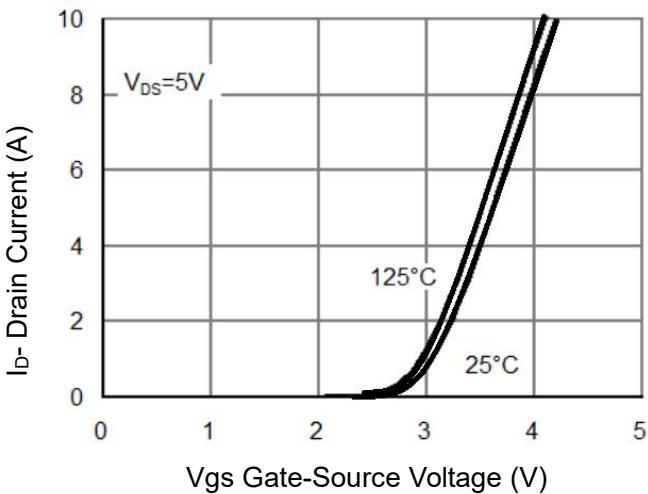


Figure 2 Transfer Characteristics

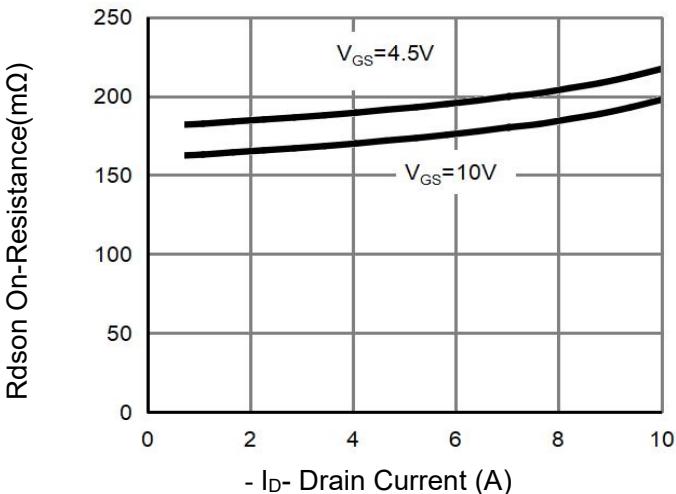


Figure 3 Rdson- Drain Current

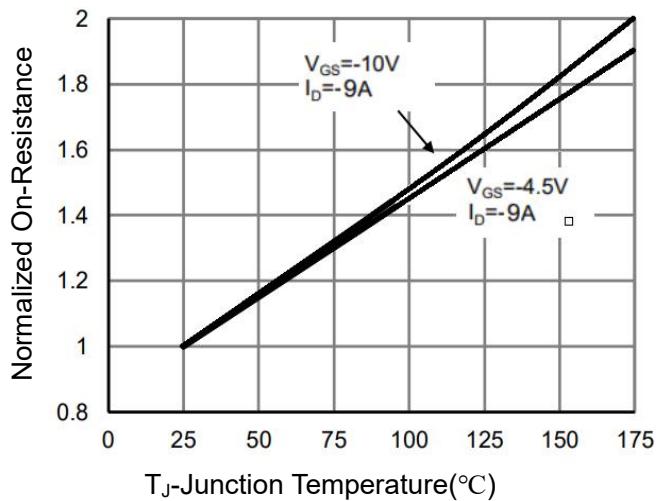


Figure 4 Rdson-Junction Temperature

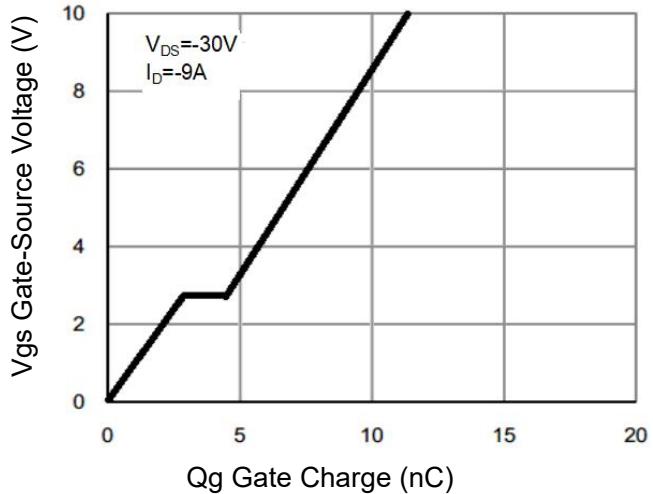


Figure 5 Gate Charge

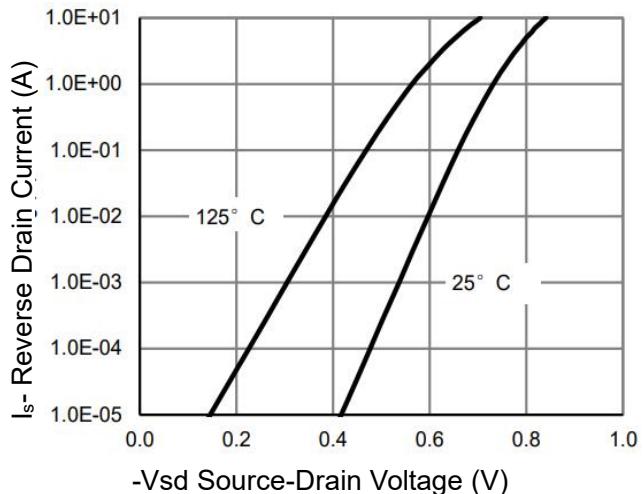


Figure 6 Source- Drain Diode Forward

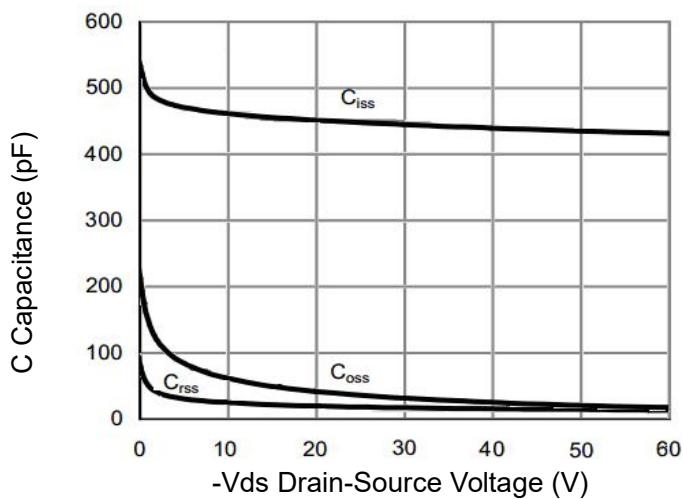
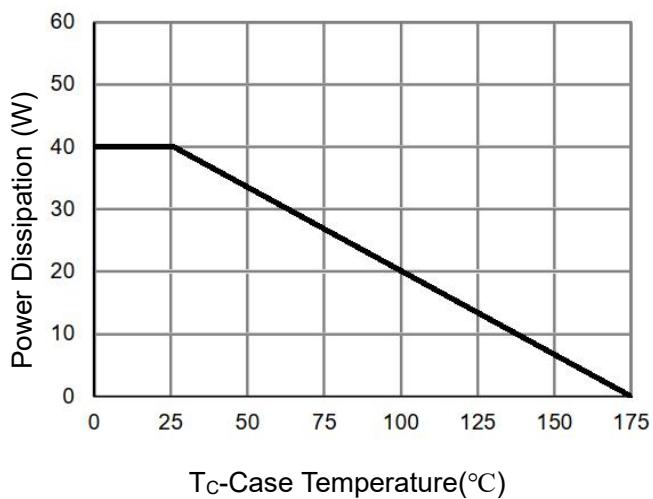


Figure 7 Capacitance vs Vds



T_c-Case Temperature(°C)

Figure 9 Power De-rating

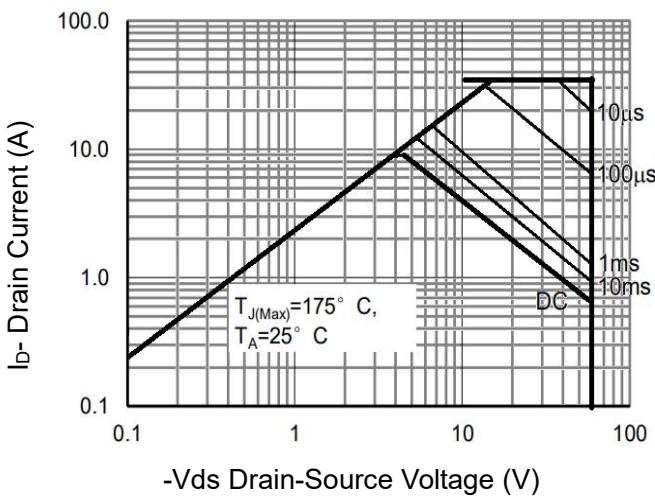
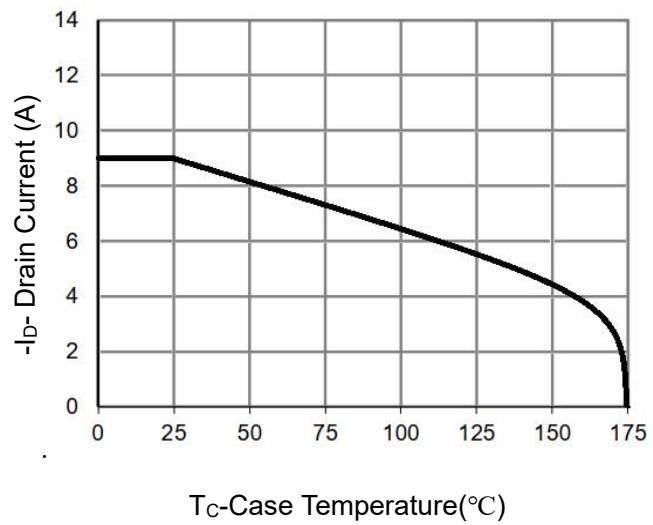


Figure 8 Safe Operation Area



T_c-Case Temperature(°C)

Figure 10 ID Current De-rating

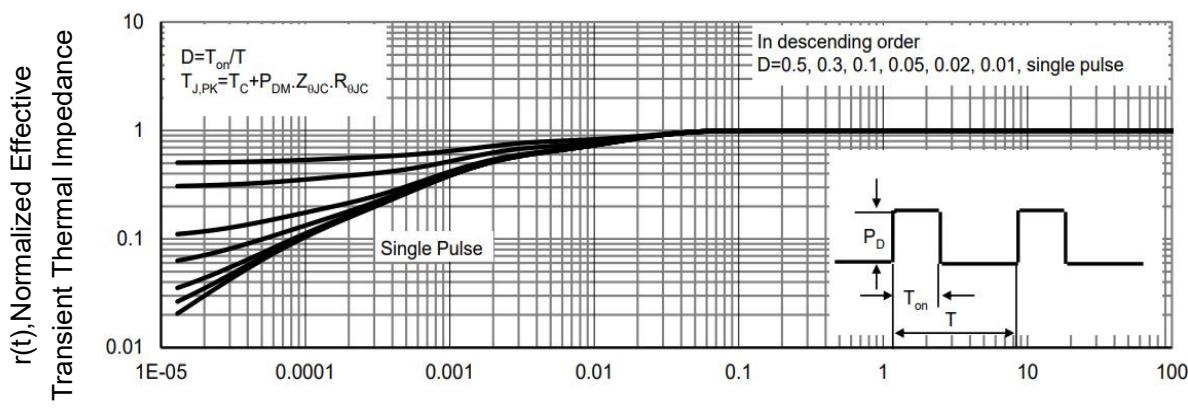
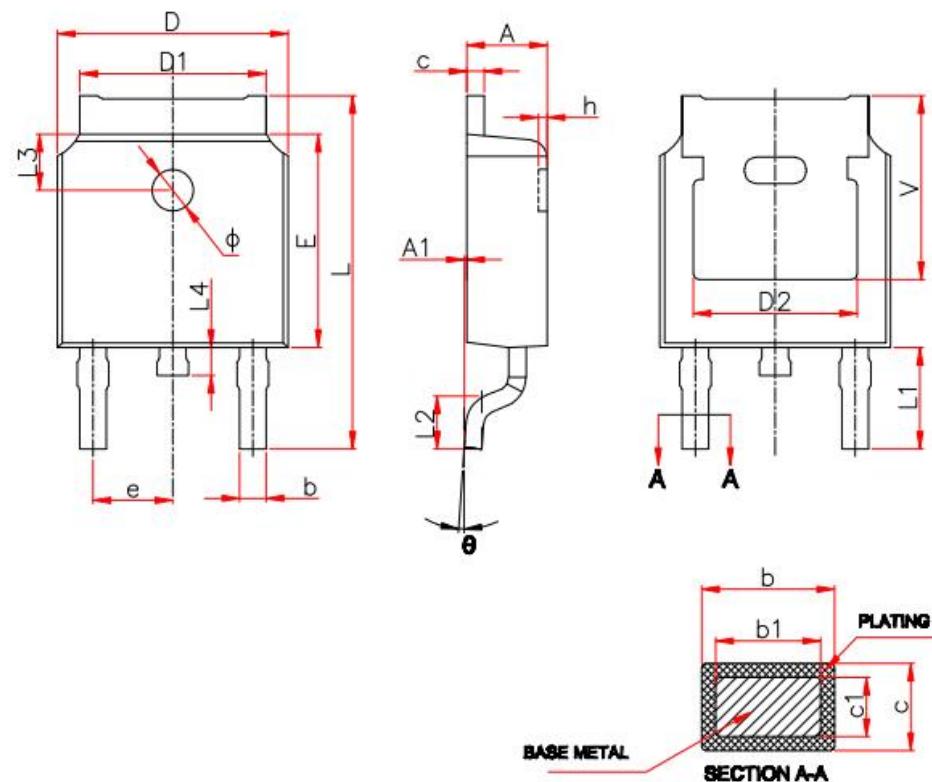


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252 Package Information



Symbol	Millimeters	
	Min.	Max.
A	2.20	2.40
A1	0.00	0.13
b	0.66	0.86
b1	0.73	0.79
c	0.46	0.58
c1	0.50	0.52
D	6.50	6.70
D1	5.10	5.46
D2	4.83 REF.	
E	6.00	6.20
e	2.19	2.39
L	9.80	10.40
L1	2.90 REF.	
L2	1.40	1.70
L3	1.60 REF.	
L4	0.60	1.00
ϕ	1.10	1.30
θ	0°	8°

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